

Form PTO-1449

INFORMATION DISCLOSURE CITATION  
IN AN APPLICATION

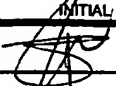

(Use several sheets if necessary)

Docket Number (Optional)  
3247.4US (97-254.04/US)Application Number  
Not yet assignedApplicant  
Wilson et al.

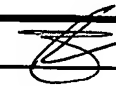
Filing Date July 7, 2003

Group Art Unit Unknown

## U.S. PATENT DOCUMENTS


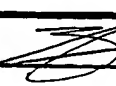
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	4,027,246	05/1977	Caccoma et al.			
	4,454,413	06/1984	Morton, Jr.			
	4,510,673	04/1985	Shils et al.			
	4,958,373	09/1990	Usami et al.			
	4,967,381	10/1990	Lane et al.			
	4,985,988	01/1991	Littlebury			
	5,003,251	03/1991	Fuoco			
	5,043,657	08/1991	Amazeen et al.			
	5,103,166	04/1992	Jeon et al.			
	5,118,369	06/1992	Shamir			
	5,175,774	12/1992	Traux et al.			
	5,197,650	03/1993	Monzen et al.			

## FOREIGN PATENT DOCUMENTS

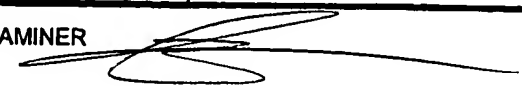
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
	5-74909	03/1993	Japan				

## OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

	English translation of abstract of Japanese Patent No. 5-74909.
	Fresenke, Dean, <i>In-Fab Identification of Silicon Wafers with Clean, Laser Marked Barcodes</i> , Advanced Semiconductor Manufacturing Conference and Workshop, 1994, IEEE/SEMI, pp. 157-60.

EXAMINER



DATE CONSIDERED

4/20/05

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance. Include copy of this form with next communication to the applicant.

<b>Form PTO-1449</b>  <b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  <i>(Use several sheets if necessary)</i>				Docket Number (Optional) <b>3247.4US (97-254.04/US)</b>		Application Number <b>Not yet assigned</b>	
Applicant <b>Wilson et al.</b>				Filing Date <b>July 7, 2003</b>		Group Art Unit <b>Unknown</b>	

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,217,834	06/1993	Higaki			
	5,226,118	07/1993	Baker et al.			
	5,271,796	12/1993	Miyashita et al.			
	5,289,113	02/1994	Meaney et al.			
	5,294,812	03/1994	Hashimoto et al.			
	5,301,143	04/1994	Ohri et al.			
	5,347,463	09/1994	Nakamura et al.			
	5,350,715	09/1994	Lee			
	5,360,747	11/1994	Larson et al.			
		5,399,531	03/1995	Wu		

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS		(Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER 	DATE CONSIDERED <b>4/20/05</b>
--------------	-----------------------------------

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance not considered. Include copy of this form with next communication to the applicant.

<b>Form PTO-1449</b>  <b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  <i>(Use several sheets if necessary)</i>			Docket Number (Optional) <b>3247.4US (97-254.04/US)</b>		Application Number <b>Not yet assigned</b>	
			Applicant <b>Wils n t al.</b>			
			Filing Date <b>July 7, 2003</b>		Group Art Unit <b>Unknown</b>	

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,420,796	05/1995	Weling et al.			
	5,448,488	09/1995	Oshima			
	5,467,304	11/1995	Uchida et al.			
	5,511,005	04/1996	Abbe et al.			
	5,642,307	06/1997	Jernigan			
	5,654,204	08/1997	Anderson			
	5,787,012	07/1998	Levitt			
	5,801,067	09/1998	Shaw et al.			
	5,805,472	09/1998	Fukasawa			
	5,837,558	11/1998	Zuniga et al.			
	5,844,803	12/1998	Beffa			
	5,856,923	01/1999	Jones et al.			
	5,890,807	04/1999	Ingel et al.			
	5,907,492	05/1999	Akram et al.			
	5,915,231	06/1999	Beffa			

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS			(Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED <b>4/20/05</b>
----------	--------------------------------

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance. Include copy of this form with next communication to the applicant.

Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE